

Notice of References Cited	Application/Control No. 10/659,271	Applicant(s)/Patent Under Reexamination YAGUCHI ET AL.	
	Examiner John L. Goodrow	Art Unit 1756	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,677,093	01-2004	Yoshino et al.	430/106.2
*	B	US-6,130,017	10-2000	Hayashi et al.	430/108.3
*	C	US-2004/0043317	03-2004	Yaguchi et al.	430/108.8
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	K	US-			
	L	US-			
	M	US-			

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	N	JP 2000-319021 11-2000	04-1999	Japan		
	O	JP 2002-129063 5-2002	09-2002	Japan		
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